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EDUCATION:

Mississippi State University	Physics	BS	1973
University of Maryland	Physics	MS	1977
University of Maryland	Physics	Ph.D.	1979

SPECIALIZATION: X-ray Spectroscopy

EXPERIENCE:

Senior Physicist, University of Washington	2001-Present
Software Scientist, EDAX, Inc.	2001-Present
Section Head, Structural Dynamics Section, NRL	1992-2001
American Institute of Physics Congressional Fellow	1991
Research Physicist, Naval Research Laboratory	1982-1992
Postdoctoral Research Assoc., Univ. of Washington	1979-1982
Graduate Research Assistant, Univ. of Maryland	1976-1979
US Arms Control and Disarmament Agency	Summer, 1974
Graduate Teaching Assistant, Univ. of Maryland	1973-1976
Management Assistant, South Central Bell Tel. Co.	1970-1973

HONORS AND COMMITTEES:

NRL Research Publication Awards	1985, 1988, 1993
Chair, Denver X-ray Conference	
Editorial Advisory Board of <i>X-ray Spectrometry</i>	
Member, International Centre for Diffraction Data	

PUBLICATIONS

1. "Absolute $2p\ 3/2$ Core Binding Energies and Work Functions of 3d Transition-Metal Surfaces," Y. Fukuda, W.T. Elam, and Robert L. Park, *Phys. Rev. B* 16, 3322 (1977).
2. "Nitrogen, Oxygen, and Carbon Monoxide Chemisorption on Polycrystalline Titanium Surfaces," Y. Fukuda, W.T. Elam, and Robert L. Park, *Appl. Surf. Sci.* 1, 278 (1978).
3. "Extended Fine Structure Above Vanadium L-Shell Appearance Potential Thresholds," P.I. Cohen, T.L. Einstein, W.T. Elam, Y. Fukuda, and Robert L. Park, *Appl. Surf. Sci.* 1, 538 (1978).
4. "Nearest Neighbor Spacing of Clean Vanadium Surfaces from Extended Appearance Potential Fine Structure," W.T. Elam, P.I. Cohen, L. Roelofs, and Robert L. Park, *Appl. Surf. Sci.* 2, 636 (1979).
5. "Extended Fine Structure Analysis Using Electron Beams," Robert L. Park, P.I. Cohen, W.T. Elam, and T.L. Einstein, *J. Crystal Growth* 45, 435 (1978).
6. "Extended Appearance-Potential Fine-Structure Analysis: Oxygen on Al (100)," M.L. denBoer, T.L. Einstein, W.T. Elam, Robert L. Park, L.D. Roelofs, and G.E. Laramore, *Phys. Rev. Lett.* 44, 496 (1980).
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11. "An X-ray Absorption Study of the Binuclear Iron Center in Deoxyhemerythrin," W.T. Elam, E.A. Stern, J.D. McCallum, and J. Sanders-Loehr, *J. Am. Chem. Soc.* 105, 1919 (1983).
12. "Anisotropy Effects in the Linearly Polarized X-ray Absorption Spectrum of Br2 Intercalated Graphite Fibers and Highly Oriented Pyrolytic Graphite," J.L. Feldman, E.F. Skelton, A.C. Ehrlich, D.D. Dominguez, W.T. Elam, S.B. Qadri, and F.W. Lytle, *Solid State Comm.* 49, 1023 (1984).

13. "Critical Properties of the Void Percolation Problem for Spheres," W.T. Elam, A.R. Kerstein, and J.J. Rehr, *Phys. Rev. Lett.* 52, 1516 (1984).
14. "Linear Compressibility Studies of Selected Transition Metal Dichalcogenides," A.W. Webb, S.B. Qadri, E.F. Skelton, W.T. Elam, Z. Rek, and W.E. Jamieson, *Mat. Res. Soc. Symp. Proc.* 22, 21 (1984).
15. "Energy-Dispersive X-Ray Diffraction with Synchrotron Radiation at Cryogenic Temperatures," E.F. Skelton, A.W. Webb, S.B. Qadri, S.A. Wolf, R.C. Lacoce, J.L. Feldman, W.T. Elam, E.R. Carpenter, Jr., and C.Y. Huang, *Rev. Sci. Instrum.* 55, 849-855 (1984).
16. "Structural Studies at Elevated Pressures and Reduced Temperatures Using Synchrotron Radiation: Application to $Ce_8Th_{11}La_{11}$," E.F. Skelton, A.W. Webb, W.T. Elam, S.A. Wolf, S.B. Qadri, C.Y. Huang, P.M. Chaikin, R.C. Lacoce, and K.A. Gschneidner, *Mat. Res. Soc. Symp. Proc.* 22, 5-9 (1984).
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19. "A Comprehensive Investigation of Residual Compounds of Br in HOPG and Graphite Filters via X-Ray Absorption," J.L. Feldman, W.T. Elam, A.C. Ehrlich, E.F. Skelton, D.D. Dominguez, S.B. Qadri, D.P.L. Chung, and F.W. Lytle, *Proc. 3rd Int. EXAFS Symp.*, 1984.
20. "Recent Advances in a Facility for High-Pressure Structural Studies using Synchrotron Radiation," E.F. Skelton, J.D. Ayers, W.T. Elam, T.L. Francavilla, S.B. Qadri, C.L. Vold, A.W. Webb, S.A. Wolf, C.Y. Huang, D. Schiferl, M.H. Manghnani, L.C. Ming, J. Balogh, and R.C. Lacoce, *High Temp.-High Press.*, 16, 527 (1984).
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49. "Structure Determination of Metastable Cobalt Films," Y. U. Idzerda, W. T. Elam, B. T. Jonker, and G. A. Prinz, *Phys. Rev. Lett.* 62, 2480-2483 (1989).
50. "Electron Detection EXAFS in He and Vacuum," W. T. Elam, J. P. Kirkland, R. A. Neiser, and P. D. Wolf, *Physica B* 158, 295-298 (1989).
51. "Identification of the Mn structure in Mn/Ag(001) superlattices," Y. U. Idzerda, B. T. Jonker, W. T. Elam, and G. A. Prinz, *J. Appl. Phys.* 67, 5385-5387 (1990).
52. "Structure Determination of Metastable Cobalt Films Deposited on GaAs," Y. U. Idzerda, B. T. Jonker, W. T. Elam, and G. A. Prinz, *J. Vac. Sci. Technol. A* 8, 1572-1576 (1990).
53. "Magnetic and Structural Investigation of Heat Treated Ion Beam Sputtered Amorphous $\text{Co}_{74}\text{Fe}_6\text{B}_{15}\text{Si}_5$ Films," V. G. Harris, S. A. Oliver, W. B. Nowak, K. H. Kim, W. T. Elam, R. Culbertson, and C. Vittoria, *IEEE Trans. on Magn.* 26 (5), 1459-61 (1990).
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57. "Surface Geometry of BaO on W(100): A Surface-Extended X-ray-Absorption Fine-Structure Study," A. Shih, C. Hor, W. Elam, J. Kirkland, and D. Mueller, *Phys. Rev. B* 44 (11), 5818-5826 (1991).
58. "FMR and EXAFS Modeling of Heat-Treated Fe-Rich and Co-Rich TM-M Thin Films," Vincent G. Haris, W. T. Elam, and Carmine Vittoria, *IEEE Transactions on Magnetics* 27 (4), 3620-3639 (1991).

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60. "Extended X-ray Absorption Fine Structure Studies of IBS Fe-Tb Alloy Films," V. G. Harris, K. D. Aylesworth, K. H. Kim, W. T. Elam, and N. C. Koon, *J. Appl. Phys.* 70 (10), 6311-6313 (1991).
61. "Direct Observation of Disorder in Perovskite-Structure Ferroelectrics," M. I. Bell, K. H. Kim, and W. T. Elam, *Ferroelectrics* 120, 103-105 (1991).
62. "Characterization of Nanocrystalline Pd by X-ray Diffraction and EXAFS," J. A. Eastman, M. R. Fitzsimmons, M. Müller-Stach, G. Wallner, and W. T. Elam, *Nanostructured Materials* 1, 47-52 (1992).
63. "Correlation Between Structure and Magnetic Anisotropy in Amorphous Fe-Tb Alloy Films," V. G. Harris, K. D. Aylesworth, W. T. Elam, and N. C. Koon, *Journal of Alloys and Compounds* 181, 431-443 (1992).
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70. "The Local Atomic Order of Cu and Fe in Heat Treated Fe_{73.5}Nb₃Cu₁Si_{13.5}B₉ Ribbons," J. D. Ayers, V. G. Harris, J. A. Sprague, and W. T. Elam, *IEEE Trans. on Mag.* 29, 2664-2666 (1993).

71. "Structural Evolution and Magnetoresistance Properties of Heat Treated $\text{Cu}_{80}\text{Co}_{15}\text{Fe}_5$ Ribbons," V. G. Harris, B. N. Das, M. Rubenstein, J. L. Goldberg, W. T. Elam, and N. C. Koon, *IEEE Trans. on Mag.* **29**, 2616-2618 (1993).
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